

Notice of References Cited	Application/Control No. 10/776,862	Applicant(s)/Patent Under Reexamination CHEN, MARY	
	Examiner Jerome Jackson Jr.	Art Unit 2815	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Driad et al "Effect of emitter...bipolar transistors" IOPP Semicond. Sci. Tech. 16 (2001) 171-175
	V	Arakawa et al "In-situ Etching...Reactor" 2001 Int. Conf. on InP and Related Compounds□□Conf. Proc.□□13th IPRM 14-18 May 2001 Nara Japan pp. 71-74
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.